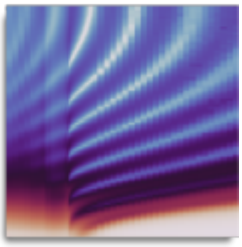
Session Program

13–15 Oct 2025



PTB-Seminar on VUV and EUV Metrology 2025

Postersession

PTB Berlin, Lecture Hall in Hermann-von-Helmholtz Building
Physikalisch-Technische Bundesanstalt (PTB) Abbestr. 2-12 10587 Berlin

Tuesday 14 October

13:00

Postersession

Session | **Location:** PTB Berlin, Gallery Hermann-von-Helmholtz Building

13:00–13:06

Reminisce - Refurbishment of Mirrors to Increase Sustainability at Light Sources - Introduction of a European collaboration project

Speaker
Silja Schmidtchen

13:06–13:12

New online polarization diagnostics for 3rd harmonic afterburner radiation

Speaker
Markus Braune

13:12–13:18

In-situ Cryogenic Cleaning of Tin-Contaminated EUV Optics

Speaker
Dr Norbert Böwering

13:18–13:24

Ultra-compact inline transmission grating spectrograph for extreme ultraviolet wavelengths

Speaker
Sascha Brose

13:24–13:30

Stand-alone extreme ultraviolet (EUV) metrological system for optical characterization of lithography materials

Speaker
Wooram Kim

13:30–13:36

Influence of experimental conditions on EUV / X-ray fluorescence yields investigated with the WDSX-300

Speaker
Valentin Stoytschew

13:36–13:42

Enhanced thin film characterization through combined S- and P-polarized EUV reflectometry

Speaker
Samira Naghdi

Location
PTB Berlin, Gallery Hermann-von-Helmholtz Building

13:42–13:48

Investigation of the Optical Constants of Amorphous SiO_2 and Y-Cut Quartz from the Extreme to the Vacuum Ultraviolet Spectral Region

Speaker
Najmeh Abbasirad

Location
PTB Berlin, Gallery Hermann-von-Helmholtz Building

13:48–13:54

Simulated XUV spectroscopy in the laboratory with a polycapillary half lens and reflection zone plates

Speaker
Jürgen Probst

13:54–14:00

X-ray standing wave coherence length in grazing exit geometry

Speaker
Timur Terentev

14:00–14:06

Exploring the soft X-ray energy range for next generation nanostructure metrology

Speaker
Dr Analía Fernández Herrero

14:06–14:12

Scatterometry Applications: Addressing Model Inaccuracies

Speaker
Maren Casfor

14:12–14:18

Calibration of a broadband reflective spectrometer for high-resolution spectral characterization of radiation sources

Speaker
Sophia Schröder

14:18–14:24

Using Monte Carlo-based Uncertainty Quantification for Free-Form XRR

Speaker
Hendrik Willem Lokhorst

Location
PTB Berlin, Gallery Hermann-von-Helmholtz Building

14:24–14:30

On the way to automatized optics adjustment at FEL sources

Speaker
Klaus Mann

Location
PTB Berlin, Gallery Hermann-von-Helmholtz Building

14:30